

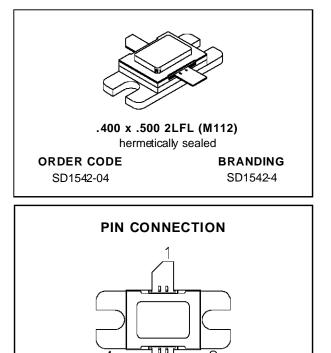
# SD1542-04

# RF & MICROWAVE TRANSISTORS AVIONICS APPLICATIONS

1. Collector

2. Base

- DESIGNED FOR HIGH POWER PULSED IFF
- 600 WATTS (min.) IFF 1030/1090 MHz
- REFRACTORY GOLD METALLIZATION
- 6.0 dB MIN. GAIN
- BALLASTING AND LOW THERMAL REISTANCE FOR RELIABILITY AND RUGGEDNESS
- 30:1 LOAD VSWR CAPABILITY AT SPECIFIED OPERATING CONDITIONS
- INPUT MATCHED, COMMON BASE CONFIGURATION



3. Emitter

4. Base

#### DESCRIPTION

The SD1542-04 is a hermetically sealed, gold metallized, silicon NPN power transistor. The SD1542-04 is designed for applications requiring high peak power and low duty cycles such as IFF. The SD1542-04 is packaged in a hermetic metal/ceramic package with internal input matching, resulting in improved broadband performance and low thermal reistance.

# **ABSOLUTE MAXIMUM RATINGS** ( $T_{case} = 25^{\circ}C$ )

Symbol	Parameter Value		Unit
Vсво	Collector-Base Voltage	65	V
V <sub>CES</sub>	Collector-Emitter Voltage 65		V
V <sub>EBO</sub>	Emitter-Base Voltage 3.5		V
lc	Device Current	40	А
PDISS	Power Dissipation	1350	W
TJ	Junction Temperature	+200	°C
T <sub>STG</sub>	Storage Temperature	– 65 to +150	°C

#### THERMAL DATA

R <sub>TH(j-c)</sub> Junction-Case Thermal Resistance	0.06	°C/W
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# SD1542-04

# **ELECTRICAL SPECIFICATIONS** ( $T_{case} = 25^{\circ}C$ )

STATIC

Symbol	Test Conditions	Value			Unit		
		Min.	Тур.	Max.	Unit		
ВVсво	$I_{C} = 25 \text{mA}$	$I_E = 0 m A$		65			V
BVEBO	$I_E = 10 mA$	$I_C = 0mA$		3.5			V
I <sub>CES</sub>	$V_{CE} = 50V$	$I_E = 0mA$		—		35	mA
h <sub>FE</sub>	$V_{CE} = 5V$	$I_C = 1A$		5		200	

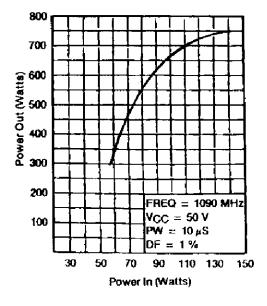
#### DYNAMIC

Symbol	Test Conditions		Value			Unit	
Symbol	Test conditions			Min.	Тур.	Max.	
Pout	f = 1090 MHz	$P_{IN} = 150 \text{ W}$	$V_{CE} = 50 V$	600	_	—	W
GP	f = 1090 MHz	$P_{IN} = 150 \text{ W}$	$V_{CE} = 50 V$	6.0	—		dB

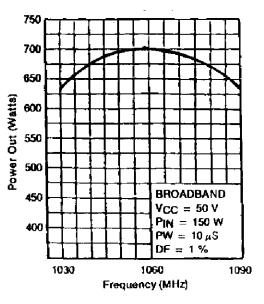
Note: Pulse Width =  $10\mu$ Sec, Duty Cyle = 1%

# TYPICAL PERFORMANCE

# POWER OUTPUT vs POWER INPUT

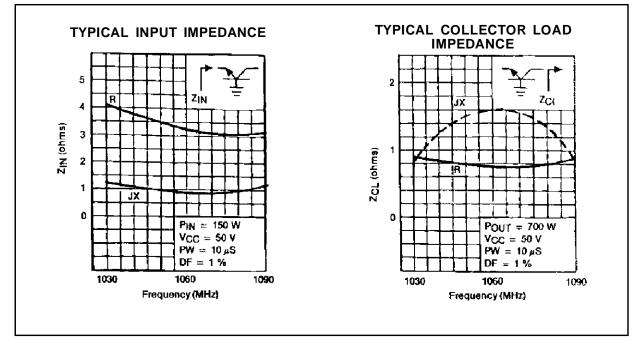


# POWER OUTPUT vs FREQUENCY



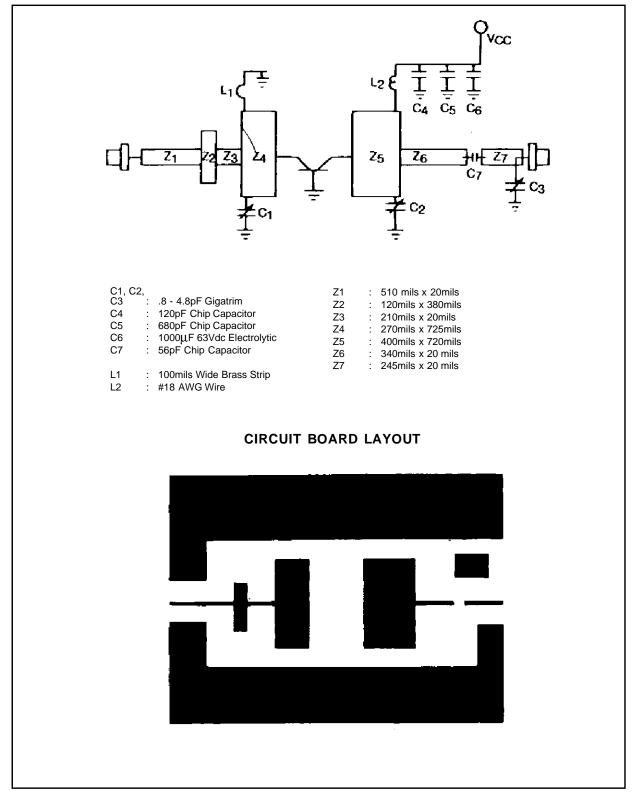


#### IMPEDANCE DATA



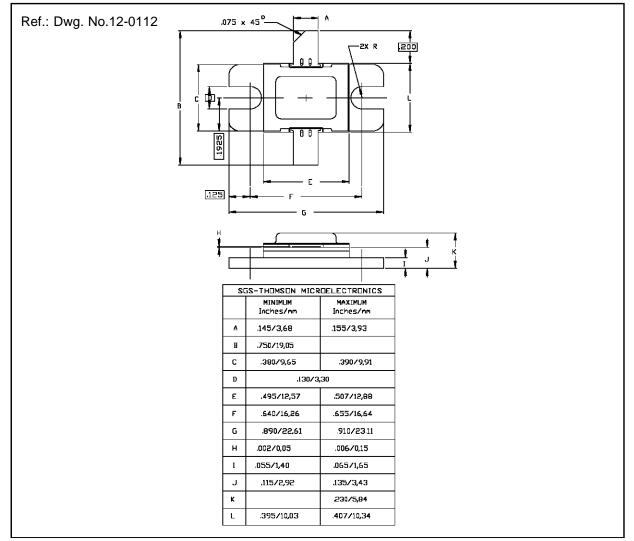


# **TEST CIRCUIT**





#### PACKAGE MECHANICAL DATA



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